


**P-Channel Enhancement-Mode
Vertical DMOS FETs**
Ordering Information

BV _{DSS} / BV _{DGS}	R _{DS(ON)} (max)	I _{D(ON)} (min)	V _{GS(th)} (max)	Order Number / Package	
				TO-92	DICE†
-20V	3.0Ω	-0.35A	-1.3V	TP0702N3	TP0702ND

† MIL visual screening available

Features

- Low threshold —1.0V max
- On resistance guaranteed at V_{GS} = 2, 3, and 5 volts
- High input impedance
- Low input capacitance —130 pF typical
- Fast switching speeds
- Low on resistance
- Free from secondary breakdown
- Low input and output leakage

Applications

- Logic level interface
- Solid state relays
- Battery operated systems
- Photo voltaic drive
- Analog switches
- General purpose line driver
- Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV _{DSS}
Drain-to-Gate Voltage	BV _{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

*Distance of 1.6 mm from case for 10 seconds.

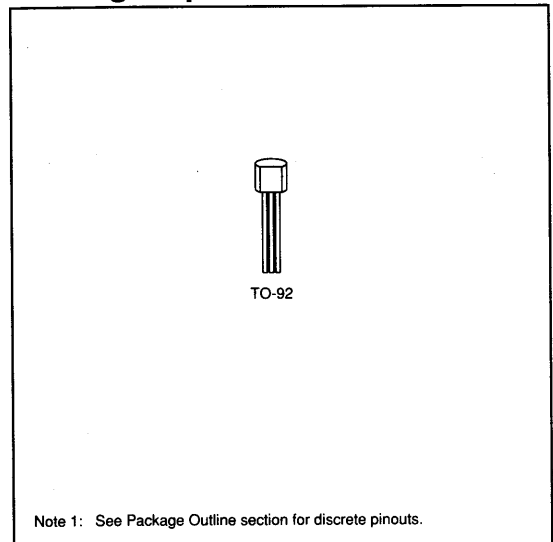
Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options

(Notes 1)



Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ $T_C = 25^\circ\text{C}$	θ_{JC} $^\circ\text{C/W}$	θ_{JA} $^\circ\text{C/W}$	I_{DR}^*	I_{DRM}
TO-92	-0.35A	-0.40A	1W	125	170	-0.035A	0.75A

* I_D (continuous) is limited by max rated T_J .

Electrical Characteristics (@ 25°C unless otherwise specified)

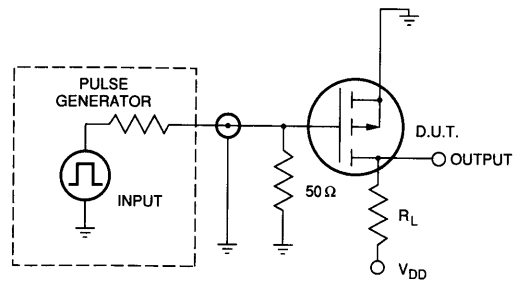
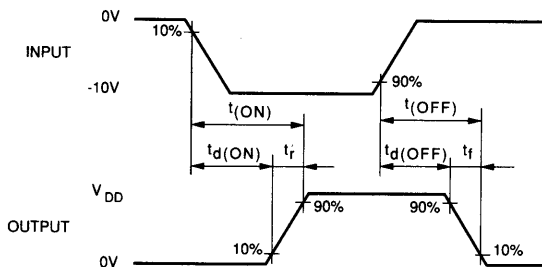
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	-20			V	$V_{GS} = 0, I_D = -1\text{mA}$
$V_{GS(th)}$	Gate Threshold Voltage	-0.7		-1.3	V	$V_{GS} = V_{DS}, I_D = -1.0\text{mA}$
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-4.5	mV/ $^\circ\text{C}$	$V_{GS} = V_{DS}, I_D = -1.0\text{mA}$
I_{GSS}	Gate Body Leakage			-100	nA	$V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$
I_{DSS}	Zero Gate Voltage Drain Current			-100	nA	$V_{DS} = 20\text{V}, V_{GS} = 0\text{V}$
				-100	μA	$V_{DS} = 0.8$ Max Rating, $V_{GS} = 0\text{V}, T_A = 125^\circ\text{C}$
$I_{D(ON)}$	ON-State Drain Current	-0.35			A	$V_{GS} = V_{DS} = 5\text{V}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			10.0	Ω	$V_{GS} = 2\text{V}, I_D = -30\text{mA}$
				5.0		$V_{GS} = 3\text{V}, I_D = -120\text{mA}$
				3.0		$V_{GS} = 5\text{V}, I_D = -250\text{mA}$
G_{FS}	Forward Transconductance	80			m Ω	$V_{DS} = 5\text{V}, I_D = -250\text{mA}$
C_{ISS}	Input Capacitance		130	200	pF	$V_{GS} = 0\text{V}, V_{DS} = -20\text{V}, f = 1\text{MHz}$
C_{OSS}	Common Source Output Capacitance		70	125		
C_{RSS}	Reverse Transfer Capacitance		30	60		
$t_{d(ON)}$	Turn-ON Delay Time			20	ns	$V_{DD} = 20\text{V}, I_D = -250\text{mA}, R_S = 50\Omega$
t_r	Rise Time			20		
$t_{d(OFF)}$	Turn-OFF Delay Time			30		
t_f	Fall Time			20		
V_{SD}	Diode Forward Voltage Drop			-1.0		

Notes:

- All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300 μs pulse, 2% duty cycle.)
- All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV _{DSS} / BV _{DGS}	R _{DS(ON)} (max)	V _{GS(th)} (max)	I _{D(ON)} (min)	Order Number / Package	
				TO-243AA*	DICE†
-20V	2.0Ω	-2.4V	-2.0A	TP2502N8	TP2502ND

* Same as SOT-89.

† MIL visual screening available.

Features

- Low threshold — -2.4V max.
- High input impedance
- Low input capacitance — 125 pF max.
- Fast switching speeds
- Low on resistance
- Free from secondary breakdown
- Low input and output leakage
- Complementary N- and P-channel devices

Applications

- Logic level interface – ideal for TTL and CMOS
- Solid state relays
- Battery operated systems
- Photo voltaic drive
- Analog switches
- General purpose line driver
- Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV _{DSS}
Drain-to-Gate Voltage	BV _{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

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Package Options

(Note 1)



TO-243AA
(SOT-89)

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ $T_C = 25^\circ\text{C}$	θ_{JC} °C/W	θ_{JA} °C/W	I_{DR}^\dagger	I_{DRM}
TO-243AA	-0.37A	-2.0A	0.55W†	227†	—	-0.37A	-2.0A

* I_D (continuous) is limited by max rated T_J .

† Mounted on FR5 board, 25mm x 19mm x 1.57mm. Significant P_D increase possible on ceramic substrate.

Electrical Characteristics (@ 25°C unless otherwise specified)

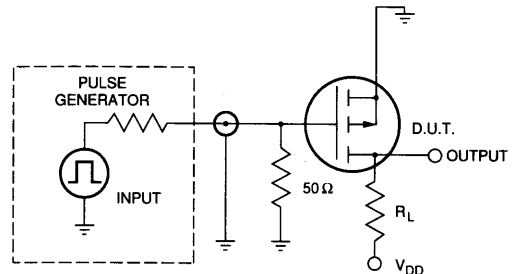
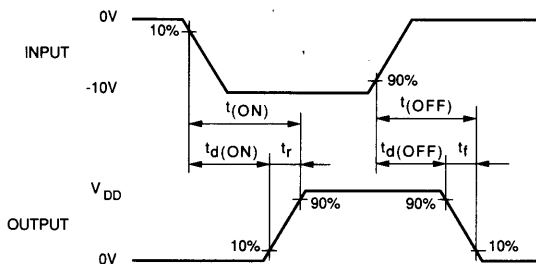
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV _{DSS}	Drain-to-Source Breakdown Voltage	TP2504	-40		V	$V_{GS} = 0, I_D = -2\text{mA}$
		TP2502	-20			
V _{GS(th)}	Gate Threshold Voltage	-1.0		-2.4	V	$V_{GS} = V_{DS}, I_D = -1\text{mA}$
$\Delta V_{GS(th)}$	Change in V _{GS(th)} with Temperature		3.0	4.5	mV/°C	$V_{GS} = V_{DS}, I_D = -1\text{mA}$
I _{GSS}	Gate Body Leakage			-100	nA	$V_{GS} = \pm 20\text{V}, V_{DS} = 0$
I _{DSS}	Zero Gate Voltage Drain Current			-10	μA	$V_{GS} = 0, V_{DS} = \text{Max Rating}$
				-1	mA	$V_{GS} = 0, V_{DS} = 0.8 \text{ Max Rating}$ $T_A = 125^\circ\text{C}$
I _{D(ON)}	ON-State Drain Current	-0.4	-0.7		A	$V_{GS} = -5\text{V}, V_{DS} = -15\text{V}$
		-2.0	-3.3			$V_{GS} = -10\text{V}, V_{DS} = -15\text{V}$
R _{DS(ON)}	Static Drain-to-Source ON-State Resistance		2.0	3.5	Ω	$V_{GS} = -5\text{V}, I_D = -250\text{mA}$
			1.5	2.0		$V_{GS} = -10\text{V}, I_D = -1\text{A}$
$\Delta R_{DS(ON)}$	Change in R _{DS(ON)} with Temperature		0.75	1.2	%/°C	$V_{GS} = -10\text{V}, I_D = -1\text{A}$
G _{FS}	Forward Transconductance	0.4	0.65		S	$V_{DS} = -15\text{V}, I_D = -1\text{A}$
C _{ISS}	Input Capacitance			125	pF	$V_{GS} = 0, V_{DS} = -15\text{V}$ $f = 1 \text{ MHz}$
C _{OSS}	Common Source Output Capacitance			70		
C _{RSS}	Reverse Transfer Capacitance			25		
t _{d(ON)}	Turn-ON Delay Time			10	ns	$V_{DD} = -15\text{V},$ $I_D = -1.0\text{A},$ $R_S = 50\Omega$
t _r	Rise Time			10		
t _{d(OFF)}	Turn-OFF Delay Time			15		
t _f	Fall Time			10		
V _{SD}	Diode Forward Voltage Drop		1.3	2.0	V	$V_{GS} = 0, I_{SD} = -1.5\text{A}$
t _{rr}	Reverse Recovery Time		300		ns	$V_{GS} = 0, I_{SD} = -1.5\text{A}$

Notes:

1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit




**P-Channel Enhancement-Mode
Vertical DMOS FETs**
Ordering Information

BV _{DSS} / BV _{DGS}	R _{DS(ON)} (max)	V _{GS(th)} (max)	I _{D(ON)} (min)	Order Number / Package	
				TO-243AA*	DICE†
-60V	3.5Ω	-2.4V	-1.5A	—	TP2506ND
-100V	3.5Ω	-2.4V	-1.5A	TP2510N8	TP2510ND

* Same as SOT-89.

† MIL visual screening available.

Features

- Low threshold — -2.4V max.
- High input impedance
- Low input capacitance — 125 pF max
- Fast switching speeds
- Low on resistance
- Free from secondary breakdown
- Low input and output leakage
- Complementary N- and P-channel devices

Applications

- Logic level interface – ideal for TTL and CMOS
- Solid state relays
- Battery operated systems
- Photo voltaic drive
- Analog switches
- General purpose line driver
- Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV _{DSS}
Drain-to-Gate Voltage	BV _{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

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Package Options

(Note 1)



TO-243AA
(SOT-89)

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ $T_C = 25^\circ\text{C}$	θ_{JC} $^\circ\text{C/W}$	θ_{JA} $^\circ\text{C/W}$	I_{DR}^*	I_{DRM}
TO-243AA	-0.28A	-1.5A	0.55W†	227†	—	-0.28A	-1.5A

* I_D (continuous) is limited by max rated T_J .

† Mounted on FR5 board, 25mm x 19mm x 1.57mm. Significant P_D increase possible on ceramic substrate.

Electrical Characteristics (@ 25°C unless otherwise specified)

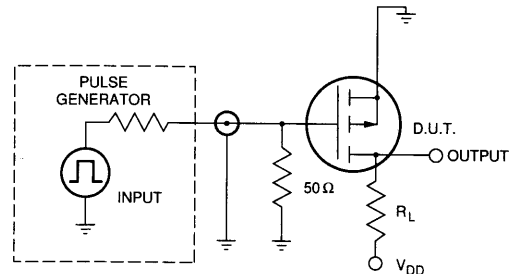
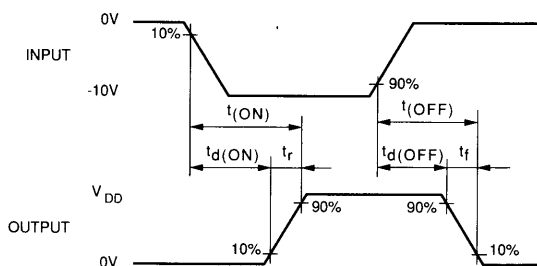
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TP2510	-100		V	$V_{GS} = 0, I_D = -2\text{mA}$
		TP2506	-60			
$V_{GS(th)}$	Gate Threshold Voltage	-1.0		-2.4	V	$V_{GS} = V_{DS}, I_D = -1\text{mA}$
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			5.0	mV/°C	$V_{GS} = V_{DS}, I_D = -1\text{mA}$
I_{GSS}	Gate Body Leakage			-100	nA	$V_{GS} = \pm 20\text{V}, V_{DS} = 0$
I_{DSS}	Zero Gate Voltage Drain Current			-10	μA	$V_{GS} = 0, V_{DS} = \text{Max Rating}$
				-1	mA	$V_{GS} = 0, V_{DS} = 0.8 \text{ Max Rating}$ $T_A = 125^\circ\text{C}$
$I_{D(ON)}$	ON-State Drain Current	-0.4	-0.6		A	$V_{GS} = -5\text{V}, V_{DS} = -25\text{V}$
		-1.5	-2.5			$V_{GS} = -10\text{V}, V_{DS} = -25\text{V}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance		5	7	Ω	$V_{GS} = -5\text{V}, I_D = -250\text{mA}$
			3	3.5		$V_{GS} = -10\text{V}, I_D = -0.75\text{A}$
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			1.7	%/°C	$V_{GS} = -10\text{V}, I_D = -0.75\text{A}$
G_{FS}	Forward Transconductance	300			m Ω	$V_{DS} = -25\text{V}, I_D = -0.75\text{A}$
C_{ISS}	Input Capacitance			125	pF	$V_{GS} = 0, V_{DS} = -25\text{V}$ $f = 1 \text{ MHz}$
C_{OSS}	Common Source Output Capacitance			70		
C_{RSS}	Reverse Transfer Capacitance			25		
$t_{d(ON)}$	Turn-ON Delay Time			10	ns	$V_{DD} = -25\text{V},$ $I_D = -1.0\text{A},$ $R_S = 50\Omega$
t_r	Rise Time			15		
$t_{d(OFF)}$	Turn-OFF Delay Time			20		
t_f	Fall Time			15		
V_{SD}	Diode Forward Voltage Drop			-1.8	V	$V_{GS} = 0, I_{SD} = -1.0\text{A}$
t_{rr}	Reverse Recovery Time		300		ns	$V_{GS} = 0, I_{SD} = -1.0\text{A}$

Notes:

- All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
- All A.C. parameters sample tested.

Switching Waveforms and Test Circuit




**P-Channel Enhancement-Mode
Vertical DMOS FETs**
Ordering Information

BV _{DSS} / BV _{DGS}	R _{DS(ON)} (max)	V _{GS(th)} (max)	I _{D(ON)} (min)	Order Number / Package	
				TO-243AA*	DICE†
-160V	12Ω	-2.4V	-0.75A	—	TP2516ND
-200V	12Ω	-2.4V	-0.75A	TP2520N8	TP2520ND

* Same as SOT-89.

† MIL visual screening available.

Features

- Low threshold — -2.4V max.
- High input impedance
- Low input capacitance — 125 pF max.
- Fast switching speeds
- Low on resistance
- Free from secondary breakdown
- Low input and output leakage
- Complementary N- and P-channel devices

Applications

- Logic level interface – ideal for TTL and CMOS
- Solid state relays
- Battery operated systems
- Photo voltaic drive
- Analog switches
- General purpose line driver
- Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV _{DSS}
Drain-to-Gate Voltage	BV _{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

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Package Options

(Note 1)


 TO-243AA
(SOT-89)

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation / @ $T_C = 25^\circ\text{C}$	θ_{JC} $^\circ\text{C/W}$	θ_{JA} $^\circ\text{C/W}$	I_{DR}^*	I_{DRM}
TO-243AA	-0.15A	-0.75A	0.55W†	227†	—	-0.15A	-0.75A

* I_D (continuous) is limited by max rated T_J .

† Mounted on FR5 board, 25mm x 19mm x 1.57mm. Significant P_D increase possible on ceramic substrate.

Electrical Characteristics (@ 25°C unless otherwise specified)

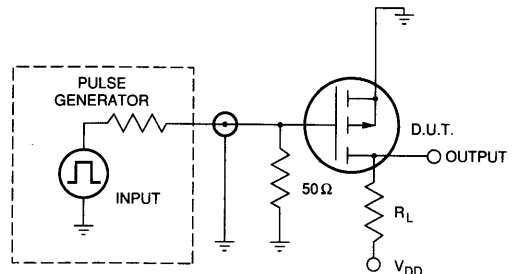
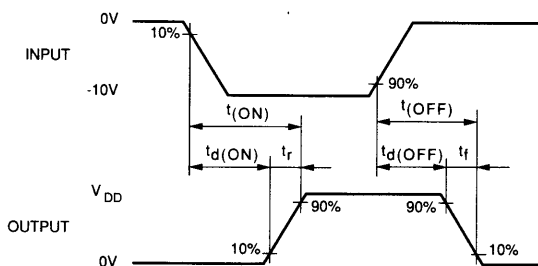
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TP2520		-200	V	$V_{GS} = 0, I_D = -2\text{mA}$
		TP2516		-160		
$V_{GS(th)}$	Gate Threshold Voltage	-1.0		-2.4	V	$V_{GS} = V_{DS}, I_D = -1\text{mA}$
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			4.5	mV/°C	$V_{GS} = V_{DS}, I_D = -1\text{mA}$
I_{GSS}	Gate Body Leakage			-100	nA	$V_{GS} = \pm 20\text{V}, V_{DS} = 0$
I_{DSS}	Zero Gate Voltage Drain Current			-10	μA	$V_{GS} = 0, V_{DS} = \text{Max Rating}$
				-1	mA	$V_{GS} = 0, V_{DS} = 0.8 \text{ Max Rating}$ $T_A = 125^\circ\text{C}$
$I_{D(ON)}$	ON-State Drain Current	-0.25			A	$V_{GS} = -4.5\text{V}, V_{DS} = -25\text{V}$
		-0.75				$V_{GS} = -10\text{V}, V_{DS} = -25\text{V}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance		12	15	Ω	$V_{GS} = -4.5\text{V}, I_D = -100\text{mA}$
			9	12		$V_{GS} = -10\text{V}, I_D = -200\text{mA}$
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			1.7	%/°C	$V_{GS} = -10\text{V}, I_D = -200\text{mA}$
G_{FS}	Forward Transconductance	100			m \bar{S}	$V_{DS} = -25\text{V}, I_D = -200\text{mA}$
C_{ISS}	Input Capacitance			125	pF	$V_{GS} = 0, V_{DS} = -25\text{V}$ $f = 1 \text{ MHz}$
C_{OSS}	Common Source Output Capacitance			85		
C_{RSS}	Reverse Transfer Capacitance			35		
$t_{d(ON)}$	Turn-ON Delay Time			10	ns	$V_{DD} = -25\text{V},$ $I_D = -1.0\text{A},$ $R_S = 50\Omega$
t_r	Rise Time			15		
$t_{d(OFF)}$	Turn-OFF Delay Time			20		
t_f	Fall Time			15		
V_{SD}	Diode Forward Voltage Drop			-1.8	V	$V_{GS} = 0, I_{SD} = -0.5\text{A}$
t_{rr}	Reverse Recovery Time		300		ns	$V_{GS} = 0, I_{SD} = -0.5\text{A}$

Notes:

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- All A.C. parameters sample tested.

Switching Waveforms and Test Circuit




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Ordering Information

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				TO-92	TO-243AA*	DICE†
-350V	25Ω	-2.4V	-0.4A	TP2535N3	—	TP2535ND
-400V	25Ω	-2.4V	-0.4A	TP2540N3	TP2540N8	TP2540ND

* Same as SOT-89.

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Features

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Absolute Maximum Ratings

Drain-to-Source Voltage	BV _{DSS}
Drain-to-Gate Voltage	BV _{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

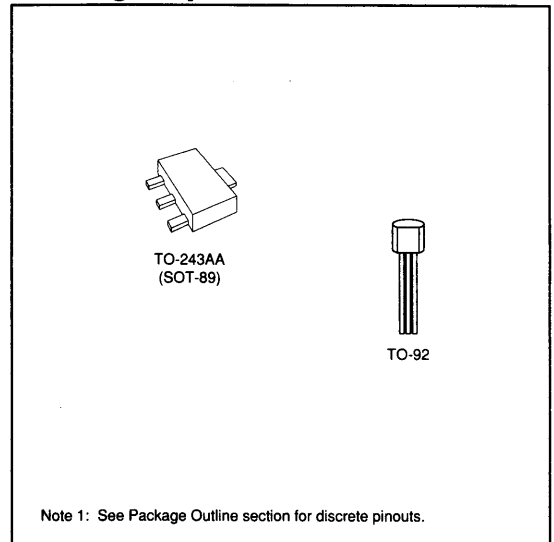
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Package Options

(Note 1)



Thermal Characteristics

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TO-92	-0.3A	-0.6A	1W	125	170	-0.3A	-0.6A
TO-243AA	-0.1A	-0.4A	0.55W†	227†	—	-0.1A	-0.4A

* I_D (continuous) is limited by max rated T_J .
 † Mounted on FR5 board, 25mm x 19mm x 1.57mm. Significant P_D increase possible on ceramic substrate.

Electrical Characteristics (@ 25°C unless otherwise specified)

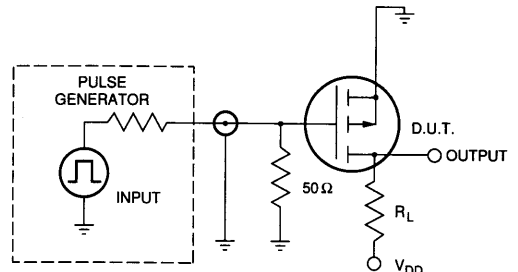
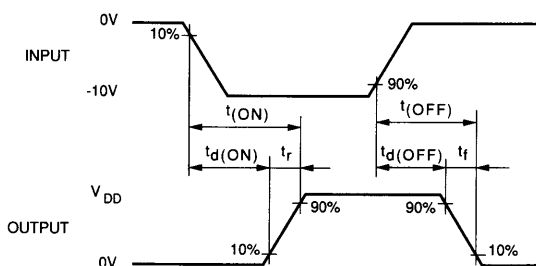
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TP2540	-400		V	$V_{GS} = 0, I_D = -2\text{mA}$
		TP2535	-350			
$V_{GS(th)}$	Gate Threshold Voltage	-1.0		-2.4	V	$V_{GS} = V_{DS}, I_D = -1\text{mA}$
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			4.8	mV/°C	$V_{GS} = V_{DS}, I_D = -1\text{mA}$
I_{GSS}	Gate Body Leakage			-100	nA	$V_{GS} = \pm 20\text{V}, V_{DS} = 0$
I_{DSS}	Zero Gate Voltage Drain Current			-10	μA	$V_{GS} = 0, V_{DS} = \text{Max Rating}$
				-1	mA	$V_{GS} = 0, V_{DS} = 0.8 \text{ Max Rating}$ $T_A = 125^\circ\text{C}$
$I_{D(ON)}$	ON-State Drain Current	-200	-300		mA	$V_{GS} = -4.5\text{V}, V_{DS} = -25\text{V}$
		-400	-550			$V_{GS} = -10\text{V}, V_{DS} = -25\text{V}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance		20	30	Ω	$V_{GS} = -4.5\text{V}, I_D = -100\text{mA}$
			19	25		$V_{GS} = -10\text{V}, I_D = -100\text{mA}$
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.75	%/°C	$V_{GS} = -10\text{V}, I_D = -100\text{mA}$
G_{FS}	Forward Transconductance	100			mS	$V_{DS} = -25\text{V}, I_D = -100\text{mA}$
C_{ISS}	Input Capacitance			125	pF	$V_{GS} = 0, V_{DS} = -25\text{V}$ $f = 1 \text{ MHz}$
C_{OSS}	Common Source Output Capacitance			70		
C_{RSS}	Reverse Transfer Capacitance			25		
$t_{d(ON)}$	Turn-ON Delay Time			10	ns	$V_{DD} = -25\text{V},$ $I_D = -100\text{mA},$ $R_S = 50\Omega$
t_r	Rise Time			10		
$t_{d(OFF)}$	Turn-OFF Delay Time			20		
t_f	Fall Time			10		
V_{SD}	Diode Forward Voltage Drop			-1.8		
t_{rr}	Reverse Recovery Time		300		ns	$V_{GS} = 0, I_{SD} = -100\text{mA}$

Notes:

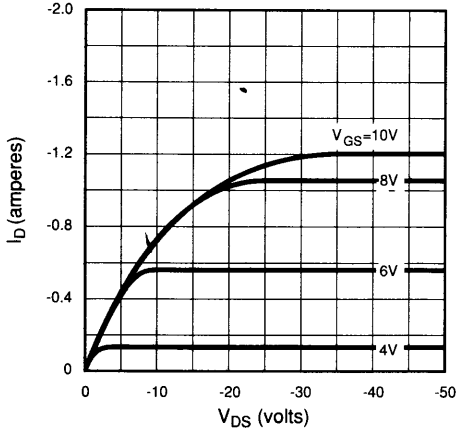
- All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
- All A.C. parameters sample tested.

Switching Waveforms and Test Circuit

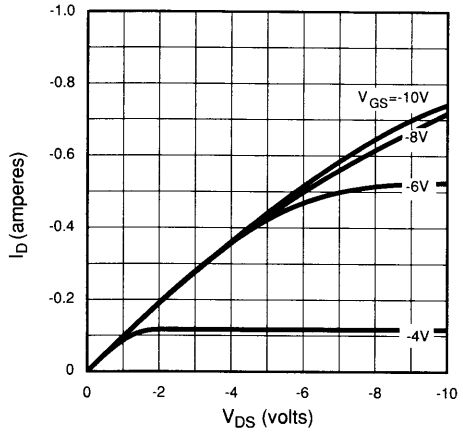


Typical Performance Curves

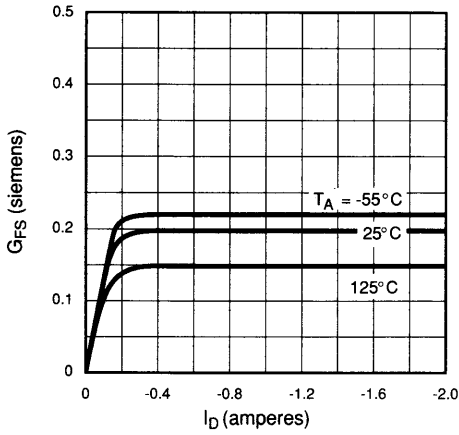
Output Characteristics



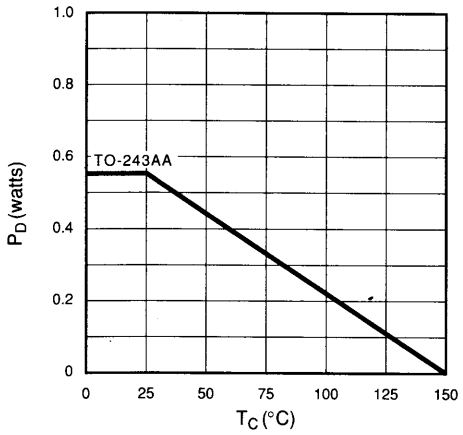
Saturation Characteristics



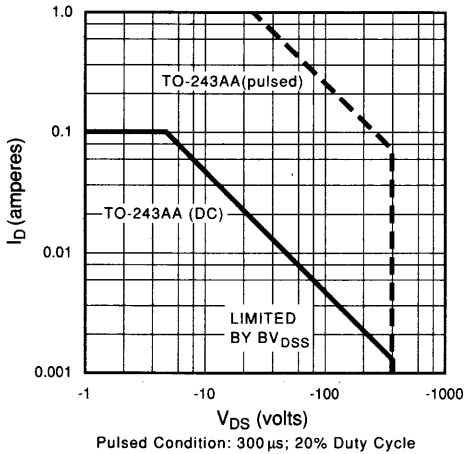
Transconductance vs. Drain Current



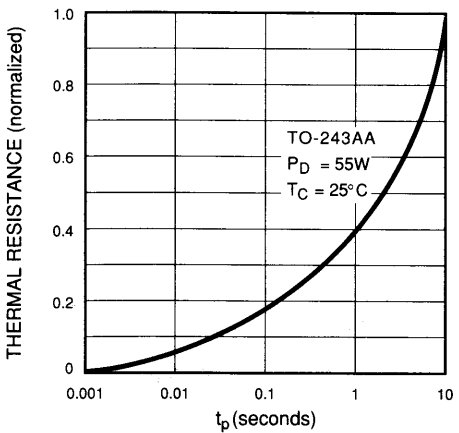
Power Dissipation vs. Case Temperature



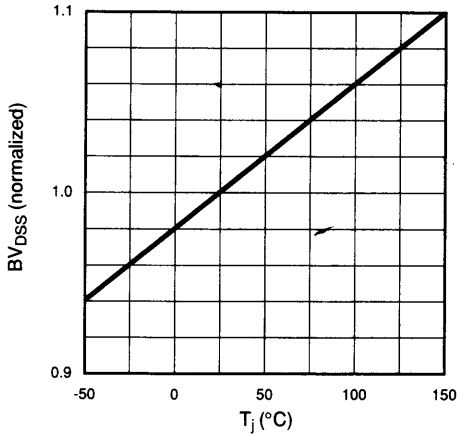
Maximum Rated Safe Operating Area



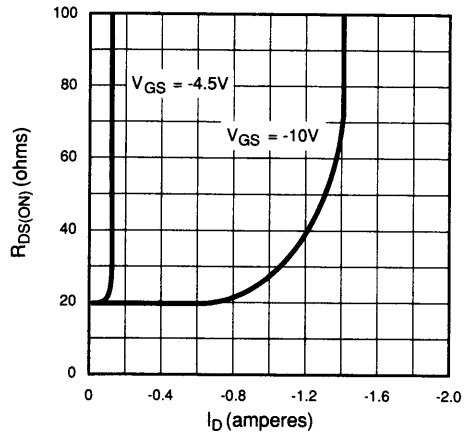
Thermal Response Characteristics



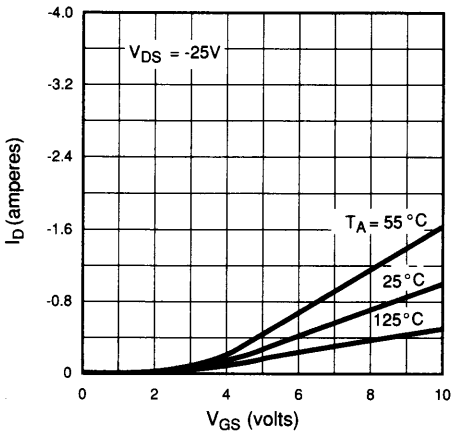
BV_{DSS} Variation with Temperature



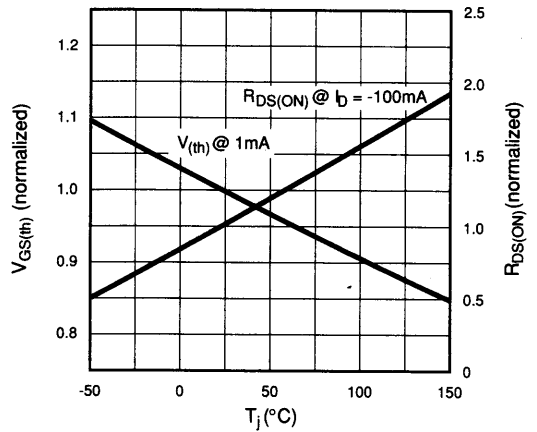
On-Resistance vs. Drain Current



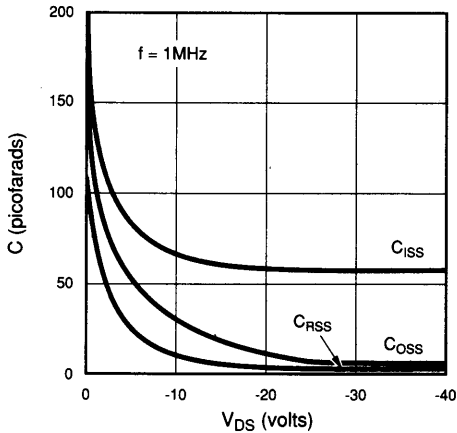
Transfer Characteristics



V_(th) and R_{DS} Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics

